## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10599310	VOLOSHIN ET AL.
Examiner	Art Unit
Young J Kim	1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES				
Search Notes	Date	Examiner		
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) -	9/29/2010	/YJK/		
see enclosed for text search strategy				
STN commercial Databases (Biosis, Medline, Embase, Embal, CAPlus) -	9/29/2010	/YJK/		
see enclosed for text search strategy				
STN search updated - see enclosed	4/28/2011	/YJK/		
Patent Databases - updated - see enclosed	4/28/2011	/YJK/		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/Young J Kim/ Primary Examiner.Art Unit 1637

U.S. Patent and Trademark Office Part of Paper No.: 20110428